

NOV 0 1 2005

Docket No.: 060188-0075

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Customer Number: 20277

FUJIWARA, MAKOTO

Confirmation Number: 5700

Application No.: 09/867,766

Group Art Unit: 2134

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Filed: May 31, 2001

Examiner: Poltorak, Piotr

For: SEMICONDUCTOR INTEGRATED CIRCUIT AND METHOD OF TESTING

SEMICONDUCTOR INTEGRATED CIRCUIT

AMENDMENT

Mail Stop RCE Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In response to the Advisory Action dated October 19, 2005 and the final Office Action dated July 1, 2005, having a three-month shortened statutory period for response set to expire on October 1, 2005, and the petition for a one-month extension of time up to and including November 1, 2005 being filed concurrently herewith, reconsideration of the above-identified application is respectfully requested in view of the following amendment and remarks.